

# PSZ22065H

650V 22A 190mΩ Si Super junction MOSFET with Zener Diode

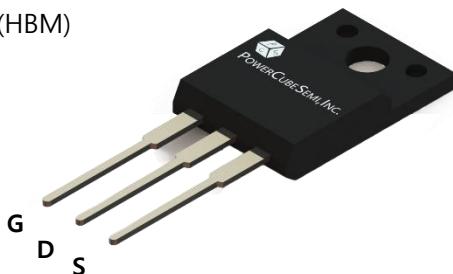


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## Features

### Si Super junction MOSFET

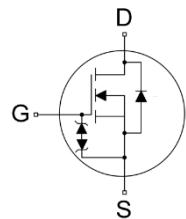
- Rated to 650V at 22Amps @ $T_c = 25^\circ\text{C}$
- Max  $R_{DS(on)} = 190 \text{ m}\Omega$
- Typ  $R_{DS(on)} = 150 \text{ m}\Omega$
- Gate Charge(Typ.  $Q_g=40 \text{ nC}$ )
- Improved dv/dt Capability
- 100% Avalanche Tested
- Excellent ESD robustness <6kV (HBM)



PKG type : TO-220F

## Application

- LCD/LED/PDP TV
- Telecom/Server Power supplies
- AC-DC Power Supply
- LED Lighting



## Description

PSZ22065H is PowerCubeSemi's second generation of high voltage Super Junction MOSFET that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, the combination of Super Junction MOSFET is suitable for various AC/DC power conversion for system miniaturization and higher efficiency

## Absolute Maximum Ratings

Symbol	Parameter	Test Condition	Value	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=1\text{mA}$	650	V
$I_D$	Drain Current	$T_c=25^\circ\text{C}$	22	A
$I_{DM}$	Pulsed Drain Current	Pulse width limited by junction temperature	88	A
$V_{GS}$	Gate-Source Voltage		$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy	$I_{AS}=9\text{A}, R_G=25\Omega, V_{DD}=50\text{V}, L=20\text{mH}$	810	mJ
$P_d$	Power Dissipation	$T_c=25^\circ\text{C}$	41.6	W
$T_J$	Operating Junction Temperature		150	°C
$T_{stg}$	Storage Temperature		-55 to 150	°C

## Package Marking and Ordering Information

Device Marking	Device	Package	Packing Method	Tape width	Quantity
PSZ22065H	PSZ22065	TO-220F*	TUBE	-	50

\* Package recommendation : TO-220F, Double stitch wiring

## Electrical Characteristics of Si MOSFET

Symbol	Parameter	Test Condition	Numerical			Unit
			Min	Typ.	Max.	
$BV_{DSS}$	Drain-source breakdown voltage	$V_{GS} = 0V, I_D = 1mA, T_C = 25^\circ C$	650	-	-	V
$I_{DSS}$	Zero gate voltage drain current	$V_{DS} = 650V, V_{GS} = 0V$	-	-	10	$\mu A$
$I_{GSS}$	Gate-source leakage current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	$\pm 5$	$\mu A$
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 1mA$	3	-	5	V
$R_{DS(ON)}$	Static drain-source on state resistance	$V_{GS} = 10V, I_D = 10A$	-	150	190	$m\Omega$
$t_{d(on)}$	Turn-on Delay time	$V_{DD} = 380 V, I_D = 10A, V_{GS} = 10 V, R_G = 4.7\Omega$	-	20	-	ns
$T_r$	Turn-on Rise time		-	8	-	
$t_{d(off)}$	Turn-off Delay time		-	64	-	
$T_f$	Turn-off Fall time		-	14	-	



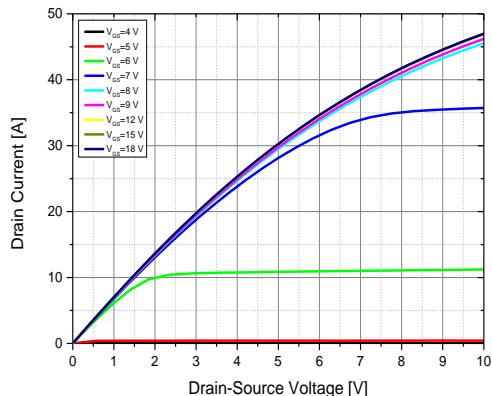
## Electrical Characteristics of Si MOSFET

Symbol	Parameter	Test Condition	Numerical		Unit
			Typ.	Max.	
$R_{\theta JC}$	Thermal resistance, Junction to case		3.0	-	°C/W
$R_g$	Gate resistance	$V_{GS} = 0V, f = 1MHz$	5	6	Ω
$C_{iss}$	Input capacitance	$V_{DS} = 380V, V_{GS} = 0V, f = 1MHz$	2000	-	pF
$C_{oss}$	Output capacitance		60	-	
$C_{rss}$	Reverse transfer capacitance		10	-	
$Q_{g(tot)}$	Total gate charge at 10V	$V_{DS} = 380V, I_D = 20A, V_{GS(on)} = 10V$	40	-	nC
$Q_{gs}$	Gate to source gate charge		8	-	
$Q_{gd}$	Gate to drain "Miller" charge		15	-	

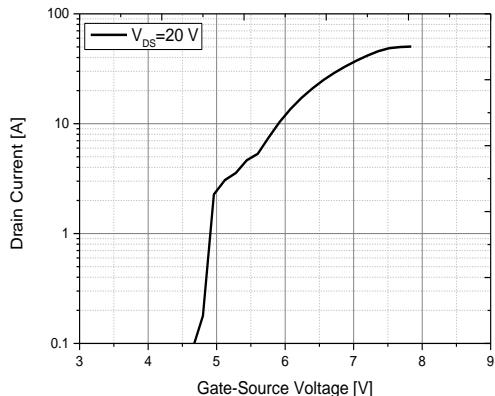
## Electrical Characteristics of Si Diode

Symbol	Parameter	Test Condition	Numerical		Unit
			Typ.	Max.	
$I_S$	Maximum continuous drain to source diode forward current		-	20	A
$I_{SM}$	Maximum pulsed drain to source diode forward current		-	50	A
$V_{SD}$	Drain to source diode forward voltage	$I_{SD} = 10A, V_{GS} = 0V$	0.9	-	V
$T_{rr}$	Reverse recovery time	$I_{SD} = 10A, V_{DD} = 400V, dI_F/dt=100A/\mu s$	310	-	ns
$Q_{rr}$	Reverse recovery charge		3.9	-	μC
$I_{rrm}$	Reverse recovery current		25	-	A

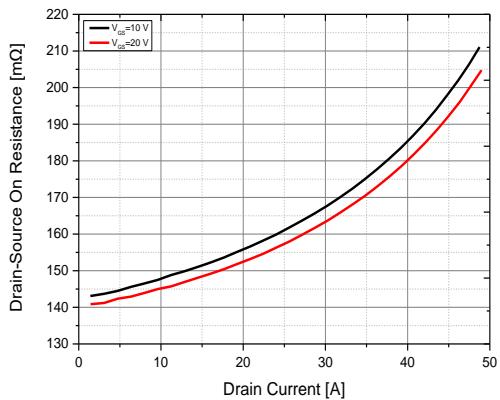
# Typical Characteristics



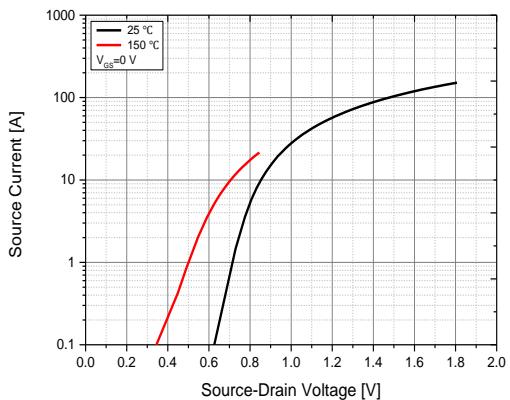
**Figure 1. On-state characteristics**



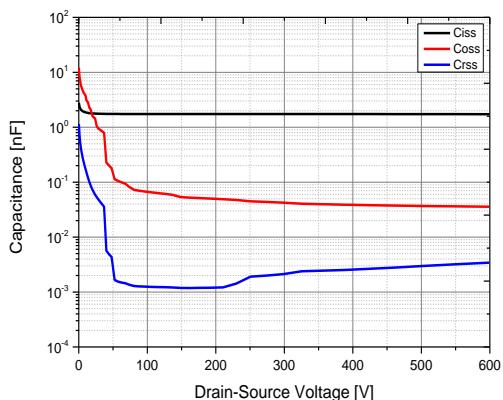
**Figure 2. Transfer Characteristics**



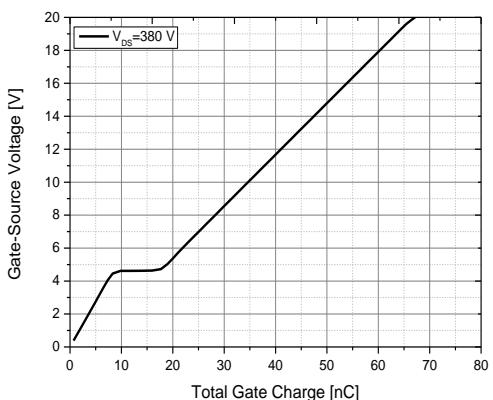
**Figure 3. On Resistance Variation vs Drain Current and Gate Voltage**



**Figure 4. Body Forward Voltage Variation vs Source Current and Temperature**

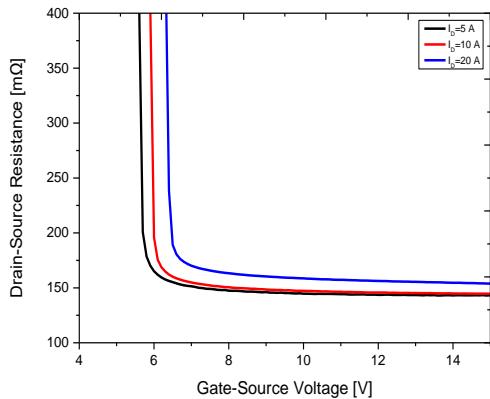


**Figure 5. Capacitance Characteristics**

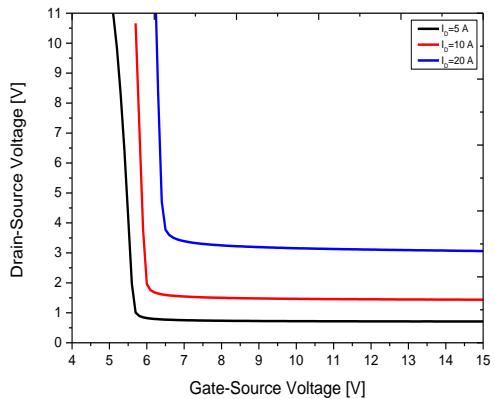


**Figure 6. Gate Charge Characteristics**

## Typical Characteristics



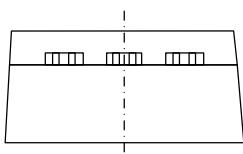
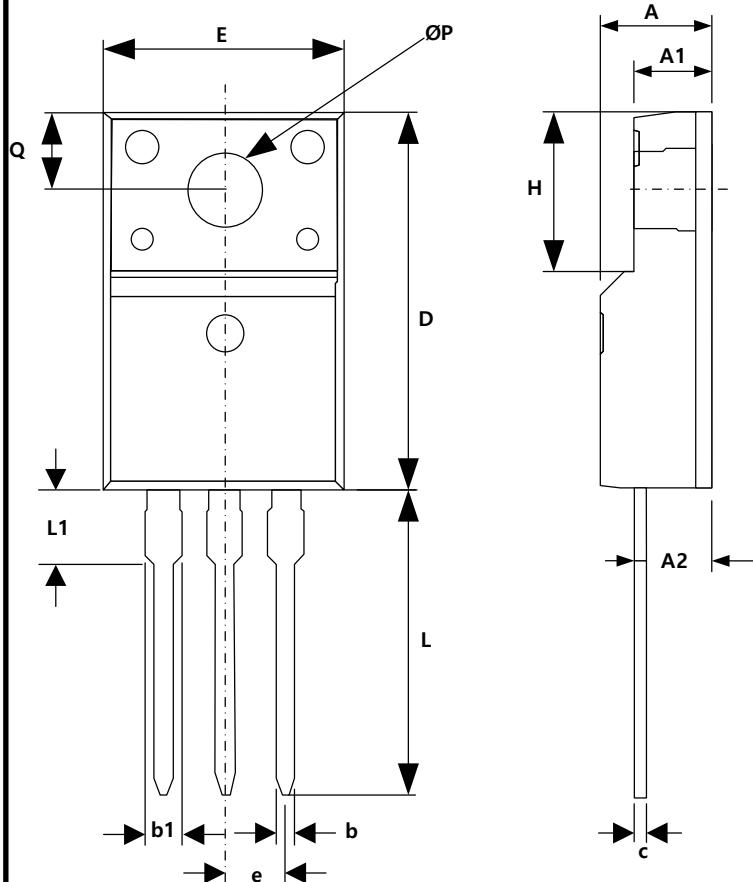
**Figure 7. Drain to Source Resistance vs Gate to Source Voltage**



**Figure 8. Drain to Source Voltage vs Gate to Source Voltage**



## Package Outline



[Unit : mm]

SYMBOL	DIMENSIONS	
	MIN	MAX
<b>A</b>	4.50	4.90
<b>A1</b>	2.34	2.74
<b>A2</b>	2.56	2.96
<b>b</b>	0.70	0.90
<b>b1</b>	1.27	1.47
<b>c</b>	0.45	0.60
<b>D</b>	15.67	16.07
<b>E</b>	9.96	10.36
<b>e</b>	2.54 BSC	
<b>H</b>	6.48	6.88
<b>L</b>	12.68	13.28
<b>L1</b>	3.03	3.43
<b>ØP</b>	3.08	3.28
<b>Q</b>	3.20	3.40

## Revision History

Version	Data of release	Description of changes
Pre 1.0	2022-03-15	Final Datasheet
Pre 1.1	2022-10-28	- $BV_{DSS}$ Test Condition Change - $R_{DS(ON)}$ Test Condition Change - Update $R_{DS(ON)}$ Typ, Max Value
Ver. 1.0	2023-02-07	- $V_{GS(th)}$ Test Condition Change - Update $V_{GS(th)}$ Min, Max Values - Update $R_{DS(ON)}$ Typ, Max Value - Final Datasheet
Ver. 1.1	2024-01-17	- Update Safe Operating Area Graph
Ver. 1.2	2024-06-26	- Update $E_{AS}, I_{DM}$ Value - Delete SOA Graph